## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10534386	NAKAUCHI ET AL.
Examiner	Art Unit

1636

SEARCHED			
Class	Subclass	Date	Examine

Mitchell, Laura M

SEARCH NOTES				
Search Notes	Date	Examiner		
Review results of STIC search for SEQ ID NO:2	12/17/2007	LMM		
EAST- USPGPub. USPat, USOCR, EPO, JPO, DERWENT (Search Notes attached)	12/18/2007	LMM		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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